



Notice of References Cited

Application/Control No.

09/830,380

Applicant(s)/Patent Under
Reexamination
ANDRE ET AL.

Examiner

Tamra L. Dicus

Art Unit

1774

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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3/24/05

4/25/01

INFORMATION DISCLOSURE CITATION

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BREV 13186

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APRIL 25, 2001

Group Art Unit

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